

Notice of Allowability

Application No.

10/642,617

Examiner

John H. Le

Applicant(s)

CHUNG, KYO YOUNG

Art Unit

2863

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to Applicant's amendment filed 09/29/2005.
2. ☒ The allowed claim(s) is/are 1,3,5-7,9,11 and 12.
3. ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some* c) ☐ None of the:
1. ☐ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. _____.
3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).
- * Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

4. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
5. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
- (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
- 1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
- (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.
- Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
6. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

- | | |
|---|---|
| 1. <input type="checkbox"/> Notice of References Cited (PTO-892) | 5. <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) |
| 2. <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 6. <input type="checkbox"/> Interview Summary (PTO-413),
Paper No./Mail Date _____ |
| 3. <input type="checkbox"/> Information Disclosure Statements (PTO-1449 or PTO/SB/08),
Paper No./Mail Date _____ | 7. <input checked="" type="checkbox"/> Examiner's Amendment/Comment |
| 4. <input type="checkbox"/> Examiner's Comment Regarding Requirement for Deposit
of Biological Material | 8. <input checked="" type="checkbox"/> Examiner's Statement of Reasons for Allowance |
| | 9. <input type="checkbox"/> Other _____ |

EXAMINER'S AMENDMENT

Response to Amendment

1. Applicant's amendment filed 09/29/2005 has been entered and carefully considered.

Claims 1, 5-7, 11-12 have been amended.

Claims 2, 4, 8, 10 have been cancelled.

Examiner's Amendment

2. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Attorney Rene A. Vazquez on 10/14/2005.

The applicant has been amended as follows:

In the Specification:

Page 2, in the Cross-reference to related applications, "US Patent Application Serial No. 10/355,059, filed January 31, 2003" has been changed to --US Patent Application Serial No. 10/355,059, filed January 31, 2003, now U.S. Patent No. 6,862,489--.

In the Abstract:

In the end of the abstract, deleted "Thus, the present invention improves the defect detection accuracy of the TFT-array testing system, even when the system's intrinsic performance is inaccurate".

In claim:

Claim 1, line 8, ("reported defects") has been changed to --"reported defects"--.

Claim 7, line 7, ("reported defects") has been changed to --"reported defects"--.

Reasons for Allowance

3. Claims 1, 3, 5-7, 9, and 11-12 are allowed.
4. The following is a statement of reasons for the indication of allowable subject matter:

Please see the previous office action and applicant's argument filed on 09/29/2005.

In combination with other limitations of the claims, the cited prior arts fails to teach incrementally adjusting the at least one thresholding parameter by a first increment value until the number of reported defects is less than the critical number of defects to yield a first thresholding parameter value; subtracting one increment value from the first thresholding parameter value to yield a second thresholding parameter value; and incrementally adjusting the second thresholding parameter value by a second increment value until the number of reported defects is less than the critical number of defects to yield an final thresholding parameter value; wherein the second increment value is smaller than the first increment value, as recited in claim(s) 1.

In combination with other limitations of the claims, the cited prior arts fails to teach incrementally adjusting the at least one thresholding parameter by a first increment value until the number of reported defects is less than the critical number of defects to yield a first thresholding parameter value; subtracting one increment value from the first thresholding parameter value to yield a second thresholding parameter value; and incrementally adjusting the second thresholding parameter value by a

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second increment value until the number of reported defects is less than the critical number of defects to yield an final thresholding parameter value; wherein the second increment value is smaller than the first increment value, as recited in claim(s) 1.

Regarding claim 1, none of the prior art of record teaches or suggests the combination of a method of improving defect detection accuracy of an electrode array testing system, wherein the electrode array defines a plurality of pixels and wherein the electrode array testing system determines if a pixel is defective based on at least one thresholding parameter that control a pass/fail criteria of each pixel during testing of TFT panel, comprising steps of adjusting the at least one thresholding parameter if the number of reported defects is greater than the critical number of defects, until the number of report defects is less than or equal to the critical number of defects, wherein the adjusting comprises incrementally adjusting the at least one thresholding parameter by a first increment value until the number of reported defects is less than the critical number of defects to yield a first thresholding parameter value; subtracting one increment value from the first thresholding parameter value to yield a second thresholding parameter value; and incrementally adjusting the second thresholding parameter value by a second increment value until the number of reported defects is less than the critical number of defects to yield an final thresholding parameter value; wherein the second increment value is smaller than the first increment value. It is these limitations as they are claimed in the combination with other limitations of claim, which have not been found, taught or suggested in the prior art of record, that make these claims allowable over the prior art.

Regarding claim 7, none of the prior art of record teaches or suggests the combination of computer-readable medium storing a program for improving defect detection accuracy of an electrode array testing system, wherein the electrode array defines a plurality of pixels and wherein the electrode array testing system determines if a pixel is defective based on at least one thresholding parameter that controls a pass/fail criteria of each pixel during testing of the TFT panel, said program comprising a second code section which if the number of reported defects is greater than the critical number of defects, adjusts the at least one thresholding parameter until the number of reported defects is less than or equal to the critical number of defects, wherein the second code section comprise a first code subsection that incrementally adjusts the at least one thresholding parameter by a first increment value until the number of reported defects is less than the critical number of defects to yield a first thresholding parameter value; a second code subsection that subtracts one increment value from the first thresholding parameter value to yield a second thresholding parameter value; and a third code subsection that incrementally adjusts the second thresholding parameter value by a second increment value until the number of reported defects is less than the critical number of defects to yield a final thresholding parameter value; wherein the second increment value is smaller than the first increment value. It is these limitations as they are claimed in the combination with other limitations of claim, which have not been found, taught or suggested in the prior art of record, that make these claims allowable over the prior art.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Contact Information

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to John H. Le whose telephone number is 571 272 2275. The examiner can normally be reached on 9:00 - 5:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John E. Barlow can be reached on 571 272 2269. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).



John H. Le

Patent Examiner-Group 2863

October 14, 2005



MICHAEL NGHIEM
PRIMARY EXAMINER